Power MOSFET30 V, 66 A, Single N-Channel, SO-8FL

Features

- Low R_{DS(ON)} to Minimize Conduction Losses
- Low Capacitance to Minimize Driver Losses
- Optimized Gate Charge to Minimize Switching Losses
- These are Pb-Free Devices

Applications

- Refer to Application Note AND8195/D
- CPU Power Delivery
- DC-DC Converters

MAXIMUM RATINGS (T_J = 25°C unless otherwise stated)

Parameter		Symbol	Value	Unit	
Drain-to-Source Voltage			V _{DSS}	30	V
Gate-to-Source Voltage			V_{GS}	±20	V
Continuous Drain Current R _{BJA}		T _A = 25°C	I _D	15	Α
(Note 1)		T _A = 85°C		11	
Power Dissipation $R_{\theta JA}$ (Note 1)		T _A = 25°C	P _D	2.17	W
Continuous Drain	1	T _A = 25°C	ID	9.5	Α
Current R _{θJA} (Note 2)	Steady	T _A = 85°C		7.0	
Power Dissipation $R_{\theta JA}$ (Note 2)	State	T _A = 25°C	P _D	0.87	W
Continuous Drain		T _C = 25°C	I _D	66	Α
Current R _{θJC} (Note 1)		T _C = 85°C		48	
Power Dissipation $R_{\theta JC}$ (Note 1)		T _C = 25°C	P _D	41.7	W
Pulsed Drain Current	T _A = 25°C, t _p = 10 μs		I _{DM}	132	Α
Operating Junction a Temperature	Operating Junction and Storage Temperature		T _J , T _{STG}	-55 to +150	°C
Source Current (Body Diode)		I _S	35	Α	
Drain to Source DV/DT		dV/dt	6	V/ns	
Single Pulse Drain-to-Source Avalanche Energy T_J = 25°C, V_{DD} = 30 V, V_{GS} = 10 V, I_L = 19 A_{pk} , L = 1.0 mH, R_G = 25 Ω		EAS	180.5	mJ	
Lead Temperature for Soldering Purposes (1/8" from case for 10 s)		TL	260	°C	

Stresses exceeding Maximum Ratings may damage the device. Maximum Ratings are stress ratings only. Functional operation above the Recommended Operating Conditions is not implied. Extended exposure to stresses above the Recommended Operating Conditions may affect device reliability.

1. Surface-mounted on FR4 board using 1 sq-in pad, 1 oz Cu.

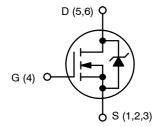
Surface-mounted on FR4 board using the minimum recommended pad size.
 *For additional information on our Pb-Free strategy and soldering details, please download the ON Semiconductor Soldering and Mounting Techniques Reference Manual, SOLDERRM/D.



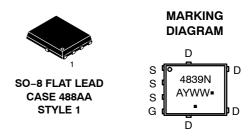
ON Semiconductor®

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V _{(BR)DSS}	R _{DS(ON)} MAX	I _D MAX
30 V	5.5 mΩ @ 10 V	00.4
30 V	9.5 m Ω @ 4.5 V	66 A



N-CHANNEL MOSFET



A = Assembly Location

Y = Year
WW = Work Week

Pb-Free Package

(Note: Microdot may be in either location)

ORDERING INFORMATION

Device	Package	Shipping [†]
NTMFS4839NT1G	SO-8FL (Pb-Free)	1500 / Tape & Reel
NTMFS4839NT3G	SO-8FL (Pb-Free)	5000 / Tape & Reel

†For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specifications Brochure, BRD8011/D.

THERMAL RESISTANCE MAXIMUM RATINGS

Parameter	Symbol	Value	Unit
Junction-to-Case (Drain)	$R_{ heta JC}$	3.0	
Junction-to-Ambient - Steady State (Note 3)	$R_{\theta JA}$	57.7	°C/W
Junction-to-Ambient - Steady State (Note)	$R_{ heta JA}$	143.4	

ELECTRICAL CHARACTERISTICS ($T_J = 25^{\circ}C$ unless otherwise specified)

Parameter	Symbol	Test Condition		Min	Тур	Max	Unit
OFF CHARACTERISTICS							
Drain-to-Source Breakdown Voltage	V _{(BR)DSS}	$V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}$		30			V
Drain-to-Source Breakdown Voltage Temperature Coefficient	V _{(BR)DSS} /				25		mV/°C
Zero Gate Voltage Drain Current	I _{DSS}	V _{GS} = 0 V,	T _J = 25 °C			1	
		V _{DS} = 24 V	T _J = 125°C			10	μΑ
Gate-to-Source Leakage Current	I _{GSS}	$V_{DS} = 0 \text{ V}, V_{GS}$	= ±20 V			±100	nA
ON CHARACTERISTICS (Note 5)					•		-
Gate Threshold Voltage	V _{GS(TH)}	$V_{GS} = V_{DS}, I_D =$: 250 μA	1.5		2.5	V
Negative Threshold Temperature Coefficient	V _{GS(TH)} /T _J				5.8		mV/°C
Drain-to-Source On Resistance	R _{DS(on)}	11.5 V	I _D = 30 A		4.5	5.5	
			I _D = 15 A		4.5		
			I _D = 30 A		8.4	9.5	mΩ
			I _D = 15 A		8.4		
Forward Transconductance	9FS	V _{DS} = 15 V, I _D = 15 A			14.7		S
CHARGES, CAPACITANCES & GATE RESIS	TANCE						•
Input Capacitance	C _{ISS}				1588		
Output Capacitance	C _{OSS}	V _{GS} = 0 V, f = 1 MHz, V _{DS} = 12 V			352		рF
Reverse Transfer Capacitance	C _{RSS}				196		1 !
Total Gate Charge	Q _{G(TOT)}				13	18	
Threshold Gate Charge	Q _{G(TH)}				1.6		
Gate-to-Source Charge	Q _{GS}	$V_{GS} = 4.5 \text{ V}, V_{DS} = 15 \text{ V}; I_D = 30 \text{ A}$			4.8		nC
Gate-to-Drain Charge	Q_{GD}				5.8		
Total Gate Charge	Q _{G(TOT)}	V _{GS} = 11.5 V, V _{DS} = 15 V; I _D = 30 A			28		nC
SWITCHING CHARACTERISTICS (Note 6)							
Turn-On Delay Time	t _{d(ON)}				12		
Rise Time	t _r	V_{GS} = 4.5 V, V_{DS} = 15 V, I_{D} = 15 A, R_{G} = 3.0 Ω			29		ns
Turn-Off Delay Time	t _{d(OFF)}				18		
Fall Time	t _f				7.0		
Turn-On Delay Time	t _{d(ON)}	V_{GS} = 11.5 V, V_{DS} = 15 V, I_{D} = 15 A, R_{G} = 3.0 Ω			8.0		
Rise Time	t _r				21		ns
Turn-Off Delay Time	t _{d(OFF)}				24		
Fall Time	t _f				7.0		

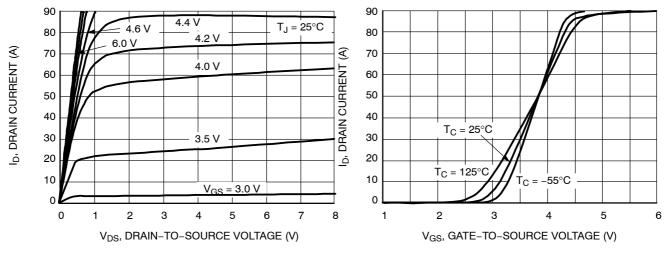
Surface-mounted on FR4 board using 1 sq-in pad, 1 oz Cu.
 Surface-mounted on FR4 board using the minimum recommended pad size.

^{5.} Pulse Test: pulse width ≤ 300 μs, duty cycle ≤ 2%.
6. Switching characteristics are independent of operating junction temperatures.

ELECTRICAL CHARACTERISTICS (T_J = 25°C unless otherwise specified)

Parameter	Symbol	Test Condition		Min	Тур	Max	Unit
DRAIN-SOURCE DIODE CHARACTE	RISTICS						
Forward Diode Voltage	V_{SD}	V _{SD} V _{GS} = 0 V, I _S = 30 A	T _J = 25°C		0.9	1.2	V
			T _J = 125°C		0.8		
Reverse Recovery Time	t _{RR}	$V_{GS} = 0 \text{ V, dIS/dt} = 100 \text{ A/}\mu\text{s,}$ $I_{S} = 30 \text{ A}$			22.2		
Charge Time	t _a				12.5		ns
Discharge Time	t _b				9.7		
Reverse Recovery Charge	Q_{RR}				10.8		nC
PACKAGE PARASITIC VALUES							
Source Inductance	L _S	T _A = 25°C			0.93		nΗ
Drain Inductance	L _D				0.005		nΗ
Gate Inductance	L _G				1.84		nΗ
Gate Resistance	R_{G}				3.3		Ω

- 5. Pulse Test: pulse width \leq 300 μ s, duty cycle \leq 2%.
- 6. Switching characteristics are independent of operating junction temperatures.





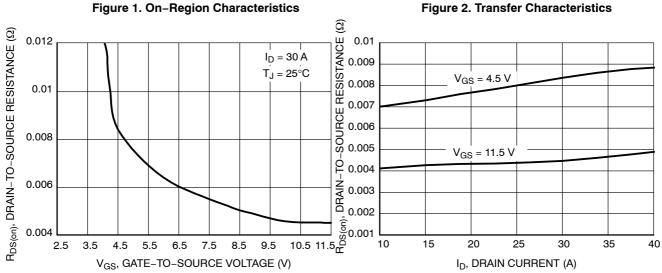


Figure 3. On-Resistance versus Gate-to-Source Voltage

Figure 4. On-Resistance versus Drain Current and Temperature

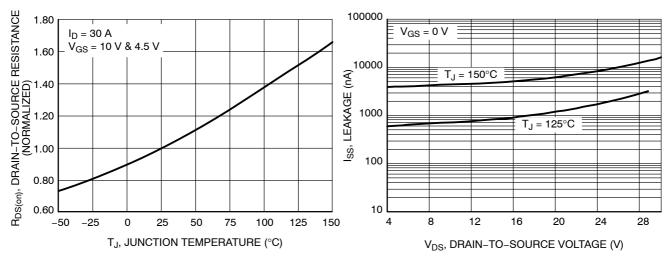
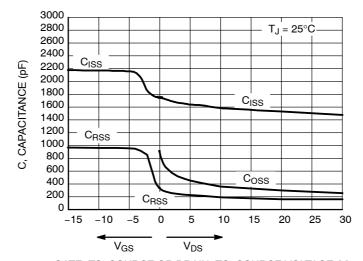


Figure 5. On-Resistance Variation with **Temperature**

Figure 6. Drain-to-Source Leakage Current versus Voltage



GATE-TO-SOURCE OR DRAIN-TO-SOURCE VOLTAGE (V) Figure 7. Capacitance Variation

20 19 18 17 16 15 14 13 12 11 10 9 8 7 6 5 4 3 2 1 0 V_{DS,} DRAIN-TO-SOURCE VOLTAGE (V) V_{GS,} GATE-TO-SOURCE VOLTAGE (V) 10 V_{DS} V_{GS} Q_{GD} Q_G $I_{D} = 30 A$ T_J = 25°C

Qq, TOTAL GATE CHARGE (nC) Figure 8. Gate-to-Source and Drain-to-Source Voltage vs. Total Gate Charge

10 12.5 15 17.5 20 22.5 25 27.5 30

5

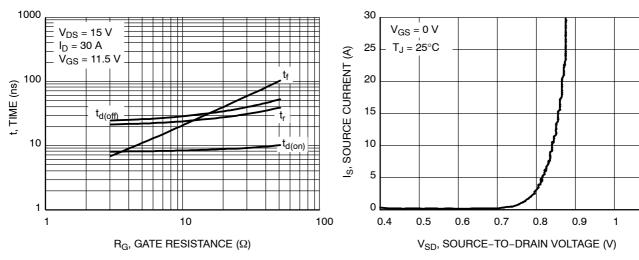


Figure 9. Resistive Switching Time Variation versus Gate Resistance

Figure 10. Diode Forward Voltage versus Current

1.1

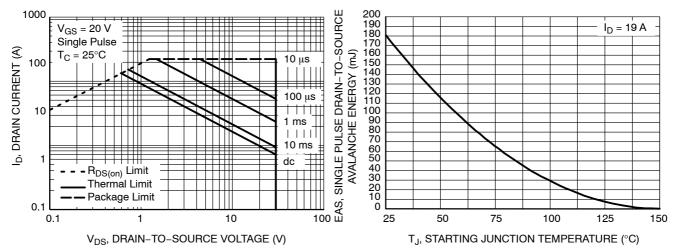
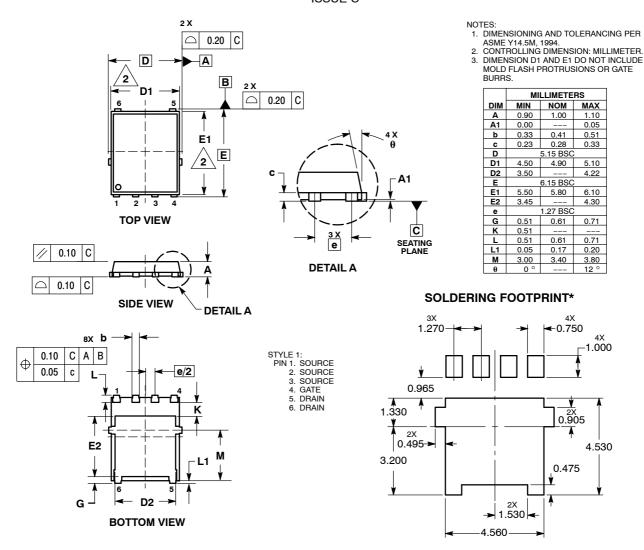


Figure 11. Maximum Rated Forward Biased Safe Operating Area

Figure 12. Maximum Avalanche Energy versus Starting Junction Temperature

PACKAGE DIMENSIONS

DFN6 5x6, 1.27P (SO8 FL)CASE 488AA-01 ISSUE C



*For additional information on our Pb-Free strategy and soldering details, please download the ON Semiconductor Soldering and Mounting Techniques Reference Manual, SOLDERRM/D.

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